

L Number	Hits	Search-Text	DB	Time-stamp
1	4	"6645676"	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/21 22:06
2	4880	(250/492.22,492.23,492.1,492.3,200).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/21 22:07
3	10828	((electron or charged-particle or (charged adj particle)) near (beam or gun)) and (mask or recticle or reticle) and stage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/21 22:09
4	52	((electron or charged-particle or (charged adj particle)) near (beam or gun)) and (mask or recticle or reticle) and stage) and (compensat\$5 near mask)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/21 22:10
5	22	((electron or charged-particle or (charged adj particle)) near (beam or gun)) and (mask or recticle or reticle) and stage) and (compensat\$5 near mask)) and (second near2 mask)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/21 22:18
6	9	((electron or charged-particle or (charged adj particle)) near (beam or gun)) and (mask or recticle or reticle) and stage) and (compensat\$5 near mask)) and (second near2 mask)) and defect\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/21 22:11
7	22	((electron or charged-particle or (charged adj particle)) near (beam or gun)) and (mask or recticle or reticle) and stage) and (compensat\$5 near mask)) and (second near2 (mask or recticle or reticle))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/21 22:19
8	3	((electron or charged-particle or (charged adj particle)) near (beam or gun)) and (mask or recticle or reticle) and stage) and (compensat\$5 near mask)) and (second near2 (mask or recticle or reticle)) and (nondefect\$5 or non-defect\$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/21 22:31
9	3	((electron or charged-particle or (charged adj particle)) near (beam or gun)) and (mask or recticle or reticle) and stage) and (compensat\$5 near mask)) and (second near2 (mask or recticle or reticle)) and (replac\$5 near5 (first near mask))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/21 22:33